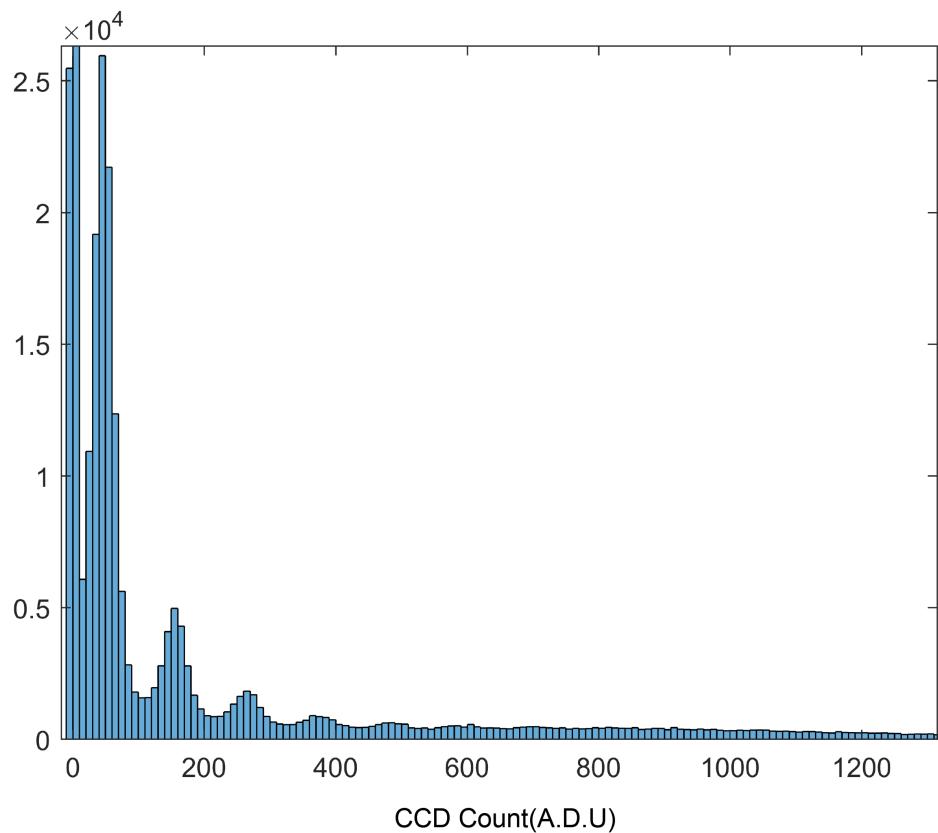
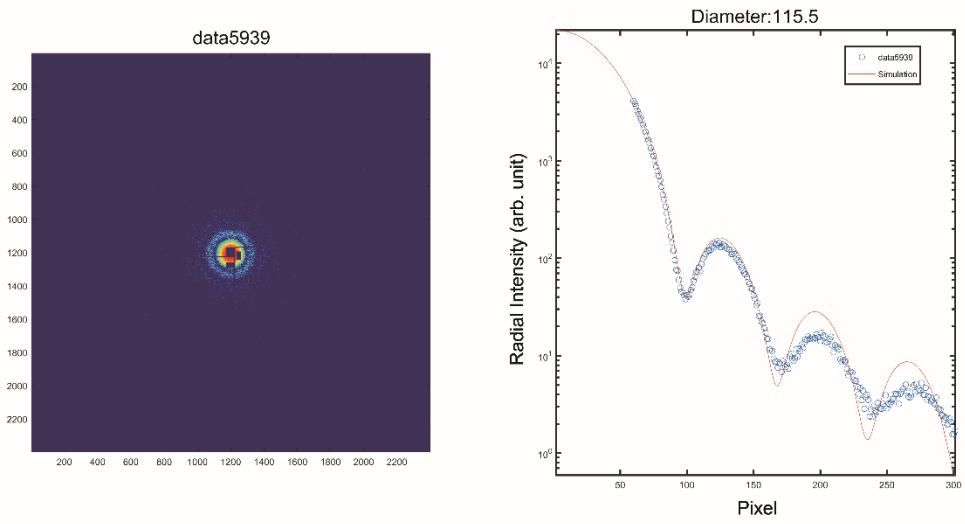


Characterizing intrinsic property of individual XFEL pulses via single-particle diffractions

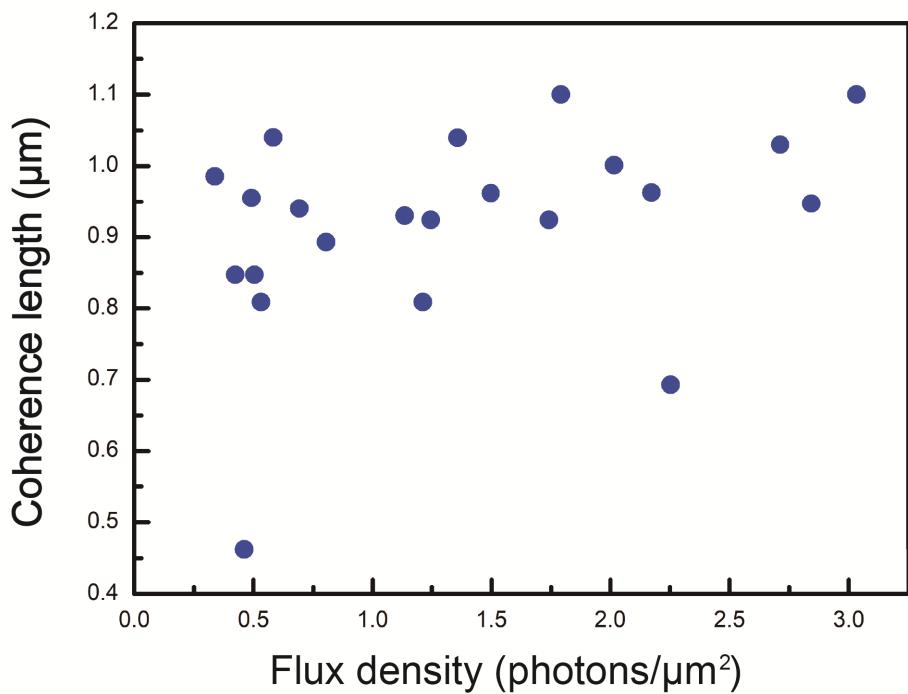
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Supplementary Figure 1: The figure above shows the CCD count histogram (binning width 10 count) of data obtained from SACLÀ. We eliminated pixels whose count is less than 20 counts (~ 0.2 photons) of signal (Dauner *et al.*, 2017), where one photon is 80 count.



Supplementary Figure 2: The left side is diffraction pattern with weak signal (run#: 5939), whose $I_0(Q = 0) = 0.33 \times 10^{10}$ photons/ μm^2 . On the right side of the figure, the data fluctuation is severe due to the low signal-to-noise ratio, and the radial intensity does not follow the analytic curve unlike Fig. 3.a of main article.



Supplementary Figure 3: The above plot shows the flux density (x-axis) obtained in section 2 and the spatial coherence length (y-axis) obtained in section 3. Both quantity does not show clear correlation.

Reference

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